



ISO7220A, ISO7220B, ISO7220C, ISO7220M ISO7221A, ISO7221B, ISO7221C, ISO7221M

SLLS755L - JULY 2006-REVISED JANUARY 2012

DUAL DIGITAL ISOLATORS

Check for Samples: ISO7220A, ISO7220B, ISO7220C, ISO7220M, ISO7221A, ISO7221B, ISO7221C, ISO7221M

FEATURES

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- 1, 5, 25, and 150-Mbps Signaling Rate Options
 - Low Channel-to-Channel Output Skew;
 1 ns max
 - Low Pulse-Width Distortion (PWD);
 1 ns max
 - Low Jitter Content; 1 ns Typ at 150 Mbps
- Typical 25-Year Life at Rated Voltage (see app. note SLLA197 and Figure 20)
- 4000-V_{PK} V_{IOTM}, 560 V_{PK} V_{IORM} per IEC 60747-5-2 (VDE 0884, Rev2)
- UL 1577, IEC 61010-1, IEC 60950-1 and CSA Approved
- 50 kV/µs Typical Transient Immunity
- Operates with 2.8-V (C-Grade), 3.3-V or 5-V Supplies

- 4 kV ESD Protection
- High Electromagnetic Immunity
- –40°C to 125°C Operating Range

APPLICATIONS

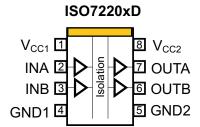
- Industrial Fieldbus
 - Modbus
 - Profibus™
 - DeviceNet™ Data Buses
- Computer Peripheral Interface
- Servo Control Interface
- Data Acquisition

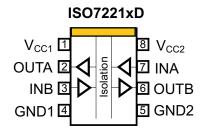
DESCRIPTION

The ISO7220 and ISO7221 are dual-channel digital isolators. To facilitate PCB layout, the channels are oriented in the same direction in the ISO7220 and in opposite directions in the ISO7221. These devices have a logic input and output buffer separated by Tl's silicon-dioxide (SiO_2) isolation barrier, providing galvanic isolation of up to 4000 V_{PK} . Used in conjunction with isolated power supplies, these devices block high voltage, isolate grounds, and prevent noise currents on a data bus or other circuits from entering the local ground and interfering with or damaging sensitive circuitry.

A binary input signal is conditioned, translated to a balanced signal, then differentiated by the capacitive isolation barrier. Across the isolation barrier, a differential comparator receives the logic transition information, then sets or resets a flip-flop and the output circuit accordingly. A periodic update pulse is sent across the barrier to ensure the proper dc level of the output. If this dc-refresh pulse is not received every 4 μ s, the input is assumed to be unpowered or not being actively driven, and the failsafe circuit drives the output to a logic high state.

The small capacitance and resulting time constant provide fast operation with signaling rates available from 0 Mbps (dc) to 150 Mbps. (1) The A-, B- and C-option devices have TTL input thresholds and a noise filter at the input that prevents transient pulses from being passed to the output of the device. The M-option devices have CMOS $V_{\rm CC}/2$ input thresholds and do not have the input noise-filter and the additional propagation delay.





(1) The signaling rate of a line is the number of voltage transitions that are made per second expressed in the units bps (bits per second).



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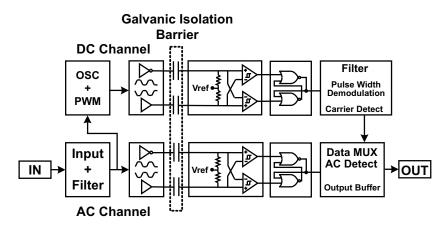
These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

DESCRIPTION CONTINUED

These devices require two supply voltages of 2.8 V (C-Grade), 3.3 V, 5 V, or any combination. All inputs are 5-V tolerant when supplied from a 2.8-V or 3.3-V supply and all outputs are 4-mA CMOS.

These devices are characterized for operation over the ambient temperature range of -40°C to 125°C.

SINGLE-CHANNEL FUNCTION DIAGRAM



AVAILABLE OPTIONS

	AVAILABLE OF HONO											
PRODUCT	MAX SIGNALING RATE	PACKAGE	INPUT THRESHOLD	CHANNEL DIRECTION	MARKED AS	ORDERING NUMBER						
ISO7220A	1 Mbps	SOIC-8	≉ 1.5 V (TTL)		17220A	ISO7220AD (rail)						
1307220A	i ivibps	3010-6	(CMOS compatible)		17220A	ISO7220ADR (reel)						
1007220D	E Mhno	SOIC-8	≉ 1.5 V (TTL)		IZOOD	ISO7220BD (rail)						
ISO7220B	5 Mbps	SOIC-8	(CMOS compatible	0	17220B	ISO7220BDR (reel)						
10070000	05 Mb	0010.0	≉ 1.5 V (TTL)	Same direction	170000	ISO7220CD (rail)						
ISO7220C	25 Mbps	SOIC-8	(CMOS compatible)		17220C	ISO7220CDR (reel)						
100700014	450 Mh	0010.0	\/ (0.(OMOS)		1700014	ISO7220MD (rail)						
ISO7220M	150 Mbps	SOIC-8	V _{CC} /2 (CMOS)		I7220M	ISO7220MDR (reel)						
1007004 A	4 845	0010.0	≉ 1.5 V (TTL)		17004 A	ISO7221AD (rail)						
ISO7221A	1 Mbps	SOIC-8	(CMOS compatible)		17221A	ISO7221ADR (reel)						
1007004D	5 NAh	0010.0	≉ 1.5 V (TTL)		IZONAD	ISO7221BD (rail)						
ISO7221B	5 Mbps	SOIC-8	(CMOS compatible)	0	17221B	ISO7221ABR (reel)						
10072240	OF Mhno	2010 0	≉ 1.5 V (TTL)	Opposite directions	170040	ISO7221CD (rail)						
ISO7221C	25 Mbps	SOIC-8	(CMOS compatible))	17221C	ISO7221CDR (reel)						
100700414	450 Mb	2010.0)/ /0 (OMOS)		1700414	ISO7221MD (rail)						
ISO7221M	150 Mbps	SOIC-8	V _{CC} /2 (CMOS)		I7221M	ISO7221MDR (reel)						



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REGULATORY INFORMATION

VDE	CSA	UL
Certified according to IEC 60747-5-2	Approved under CSA Component Acceptance Notice 5A	Recognized under UL 1577 Component Recognition Program
Basic Insulation Maximum Transient Overvoltage, 4000 V _{PK} Maximum Surge Voltage, 4000 V _{PK} Maximum Working Voltage, 560 V _{PK}	Evaluated to CSA 60950-1-07 and IEC 60950-1 (2nd Ed.) for products with working voltages \leq 125 V_{RMS} for reinforced insulation or \leq 400 V_{RMS} for basic insulation	Single Protection, 2500 V _{RMS} ⁽¹⁾
File Number: 40016131	File Number: 220991	File Number: E181974

⁽¹⁾ Production tested ≥3000 V_{RMS} for 1 second in accordance with UL 1577.

ABSOLUTE MAXIMUM RATINGS(1)

					VALUE	UNIT
V _{CC}	Supply voltage ⁽²⁾	, V _{CC1} , V _{CC2}			-0.5 to 6	V
VI	Voltage at IN, Ol	JT			-0.5 to 6	V
Io	Output current			±15	mA	
	Electrostatic	Human Body Model	Electrostatic discharge JEDEC Standard 22, Test Method A114-C.01		±4	kV
ESD	discharge	Field-Induced-Charged Device Model	JEDEC Standard 22, Test Method C101	All pins	±1	
		Machine Model	ANSI/ESDS5.2-1996		±200	V
T_{J}	Maximum junctio	•	170	°C		

⁽¹⁾ Stresses beyond those listed under absolute maximum ratings may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under recommended operating conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

RECOMMENDED OPERATING CONDITIONS

			MIN	TYP	MAX	UNIT
V _{CC}	Supply voltage ⁽¹⁾ , V _{CC1} , V _{CC2}	ISO722xA, ISO722xB, ISO722xM	3		5.5	V
00		ISO722xC	2.8		5.5	
I _{OH}	High-level output current		-4			mA
I _{OL}	Low-level output current				4	mA
		ISO722xA	1	0.67		μs
	langut and a middle (2)	ISO722xB	200	100		
t _{ui}	Input pulse width (2)	ISO722xC	40	33		ns
		ISO722xM	6.67	5	_	
		ISO722xA	0	1500	1000	kbps
4.4	Cianalia a sata (2)	ISO722xB	0	10	5	
1/t _{ui}	Signaling rate ⁽²⁾	ISO722xC	0	30	25	Mbps
		ISO722xM	0	200	1000	
V_{IH}	High-level input voltage	ISO722xA, ISO722xB,	2		V_{CC}	V
V _{IL}	Low-level input voltage	ISO722xC	0		0.8	V
V _{IH}	High-level input voltage	100700 14	0.7 V _{CC}		V_{CC}	V
V_{IL}	Low-level input voltage	ISO722xM	0		0.3 V _{CC}	V
T_{J}	Junction temperature	Junction temperature			150	°C
Н	External magnetic field-strength immunity per IEC 6	1000-4-8 & IEC 61000-4-9 certification			1000	A/m

⁽¹⁾ For the 5-V operation, V_{CC1} or V_{CC2} is specified from 4.5 V to 5.5 V. For the 3.3-V operation, V_{CC1} or V_{CC2} is specified from 3 V to 3.6 V. For the 2.8-V operation, V_{CC1} or V_{CC2} is specified at 2.8 V.

⁽²⁾ All voltage values except differential I/O bus voltages are with respect to network ground terminal and are peak voltage values.

⁽²⁾ Typical signaling rate and Input pulse width are measured at ideal conditions at 25°C.



ELECTRICAL CHARACTERISTICS: V_{CC1} and V_{CC2} at 5-V⁽¹⁾ OPERATION

over recommended operating conditions (unless otherwise noted)

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
SUPPL	Y CURRENT	•					
	ISO7220x	0:	V V 220V 221224		1	2	
	ISO7221	Quiescent	$V_I = V_{CC}$ or 0 V, no load		8.5	17	
	ISO7220A, ISO7220B	4 1 1 1 1 1 1 1	0.5 MHz larget Olayla Olayla Olayla a larget		2	3	
I _{CC1}	ISO7221A, ISO7221B	1 Mbps	0.5 MHz Input Clock Signal, no load		10	18	
	ISO7220C, ISO7220M	OF Mhma	12.5 MHz Input Clock Signal, no		4	9	
	ISO7221C, ISO7221M	25 Mbps	load		12	22	A
	ISO7220x	0	V V 0V 1 1		16	31	mA
	ISO7221x	Quiescent	$V_I = V_{CC}$ or 0 V, no load		8.5	8.5 17 17 32 10 18 20 34	
	ISO7220A, ISO7220B	4 1 1 1 1 1 1 1	0.5 MHz larget Olayla Olayla Olayla a larget		17	32	
I _{CC2}	ISO7221A, ISO7221B	1 Mbps	0.5 MHz Input Clock Signal, no load		10		
	ISO7220C, ISO7220M	OF Mhma	12.5 MHz Input Clock Signal, no		20	34	
	ISO7221C, ISO7221M	25 Mbps	load		12	17 3 18 9 22 31 17 32	
	LPak lavel sydnet veltere	<u> </u>	I _{OH} = -4 mA, See Figure 1	V _{CC} - 0.8	4.6		.,
V_{OH}	High-level output voltage		I _{OH} = -20 μA, See Figure 1	V _{CC} - 0.1	5		V
V	Lavida al autorituralta da		I _{OL} = 4 mA, See Figure 1		0.2	0.4	
V_{OL}	Low-level output voltage		I _{OL} = 20 μA, See Figure 1		0	0.1	V
V _{I(HYS)}	Input voltage hysteresis				150		mV
I _{IH}	High-level input current		INI france O V/ to V/			10	
I _{IL}	Low-level input current		IN from 0 V to V _{CC}	-10			μA
Cı	Input capacitance to ground		IN at V_{CC} , $V_I = 0.4 \sin (4E6\pi t)$		1		pF
CMTI	Common-mode transient immunity		V _I = V _{CC} or 0 V, See Figure 3	25	50		kV/μs

⁽¹⁾ For the 5-V operation, V_{CC1} or V_{CC2} is specified from 4.5 V to 5.5 V.

SWITCHING CHARACTERISTICS: V_{CC1} and V_{CC2} at 5-V OPERATION

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{pLH} , t _{pHL}	Propagation delay	ISO722xA		280	405	475	
PWD	Pulse-width distortion $ t_{pHL} - t_{pLH} ^{(1)}$				1 12 55 1	14	
t _{pLH} , t _{pHL}	Propagation delay	ISO722xB		42	55	70	
PWD	Pulse-width distortion $ t_{pHL} - t_{pLH} ^{(1)}$		See Figure 1		1	3	ns
t _{pLH} , t _{pHL}	Propagation delay	ISO722xC		22	32	42	115
PWD	Pulse-width distortion $ t_{pHL} - t_{pLH} ^{(1)}$				1	2	
t _{pLH} , t _{pHL}	Propagation delay	ISO722xM		6	10	16	
PWD	Pulse-width distortion $ t_{pHL} - t_{pLH} ^{(1)}$				0.5	1	
		ISO722xA				180	
	Dort to part alray (2)	ISO722xB				17	
t _{sk(pp)}	Part-to-part skew (2)	ISO722xC				10	ns
		ISO722xM				3	

⁽¹⁾ Also referred to as pulse skew.

⁽²⁾ t_{sk(pp)} is the magnitude of the difference in propagation delay times between any specified terminals of two devices when both devices operate with the same supply voltages, at the same temperature, and have identical packages and test circuits.





SWITCHING CHARACTERISTICS: V_{CC1} and V_{CC2} at 5-V OPERATION (continued)

over recommended operating conditions (unless otherwise noted)

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
		ISO722xA			3	15	ns
t _{sk(o)}	Channel-to-channel output skew (3)	ISO722xB			0.6	3	
		ISO722xC/M			0.2	1	
t _r	Output signal rise time		0 5 4		1	1	
t _f	Output signal fall time		See Figure 1		1		ns
t _{fs}	Failsafe output delay time from input power loss		See Figure 2		3		μs
t _{jit(pp)}	Peak-to-peak eye-pattern jitter	ISO722xM	150 Mbps PRBS NRZ data, 5-bit max same polarity input, both channels, See Figure 4, Figure 17	1			ns
Jit(PP)	, , ,		150 Mbps unrestricted bit run length data input, both channels, See Figure 4		2	<u> </u>	

⁽³⁾ t_{sk(0)} is the skew between specified outputs of a single device with all driving inputs connected together and the outputs switching in the same direction while driving identical specified loads.

ELECTRICAL CHARACTERISTICS: V_{CC1} at 5 V, V_{CC2} at 3.3 V⁽¹⁾ OPERATION

	PARAMETER	TES	T CONDITIONS	MIN	TYP	MAX	UNIT
SUPPLY	CURRENT						
	ISO7220x	Ouissant	\/ \/ or 0 \/ no lood		1	2	
	ISO7221x	Quiescent	V _I = V _{CC} or 0 V, no load		8.5	17	
	ISO7220A, ISO7220B	4.045	0.5 MHz Input Clock Signal, no		2	3	
I _{CC1}	ISO7221A, ISO7221B	1 Mbps	load		10	18	
	ISO7220C, ISO7220M	05 Mb	12.5 MHz Input Clock Signal,		4	9	
	ISO7221C, ISO7221M	25 Mbps	no load		12	22	A
	ISO7220x	Outros	V V -= 0 V == 1==d		8	18	mA
	ISO7221x	Quiescent	V _I = V _{CC} or 0 V, no load		4.3	9.5	
	ISO7220A, ISO7220B	4 Mb	0.5 MHz Input Clock Signal, no		9	19	
I _{CC2}	ISO7221A, ISO7221B	1 Mbps	load		5 1	11	
	ISO7220C, ISO7220M	05 Mb	12.5 MHz Input Clock Signal,		10	20	
	ISO7221C, ISO7221M	25 Mbps	no load		6	12	
		ISO7220x	I _{OH} = -4 mA, See Figure 1	V _{CC} - 0.4			
V_{OH}	High-level output voltage	ISO7221x (5-V side)		V _{CC} - 0.8			V
			I _{OH} = –20 μA, See Figure 1	V _{CC} - 0.1			
V	Low-level output voltage		I _{OL} = 4 mA, See Figure 1			0.4	V
V_{OL}	Low-level output voltage		I _{OL} = 20 μA, See Figure 1			0.1	V
$V_{I(HYS)}$	Input voltage hysteresis				150		mV
I _{IH}	High-level input current		IN from 0 \/ to \/			10	
I _{IL}	Low-level input current		IN from 0 V to V _{CC}	-10			μA
Cı	Input capacitance to ground		IN at V_{CC} , $V_{I} = 0.4 \sin (4E6\pi t)$		1		pF
CMTI	Common-mode transient immunity		V _I = V _{CC} or 0 V, See Figure 3	15	40		kV/μs

⁽¹⁾ For the 5-V operation, V_{CC1} or V_{CC2} is specified from 4.5 V to 5.5 V. For the 3.3-V operation, V_{CC1} or V_{CC2} is specified from 3 V to 3.6 V.



SWITCHING CHARACTERISTICS: V_{CC1} at 5 V, V_{CC2} at 3.3 V OPERATION

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{pLH} , t _{pHL}	Propagation delay	ISO722xA		285	410	480	
PWD	Pulse-width distortion t _{pHL} - t _{pLH} ⁽¹⁾				1	14	
t _{pLH} , t _{pHL}	Propagation delay	ISO722xB		45	58	480	
PWD	Pulse-width distortion $ t_{pHL} - t_{pLH} ^{(1)}$		See Figure 1		1	3	no
t _{pLH} , t _{pHL}	Propagation delay	ISO722xC	See Figure 1	25	36	48	ns
PWD	Pulse-width distortion $ t_{pHL} - t_{pLH} ^{(1)}$				1	2	
t _{pLH} , t _{pHL}	Propagation delay	ISO722xM		7	12	20	
PWD	Pulse-width distortion t _{pHL} - t _{pLH} ⁽¹⁾				0.5	1	
		ISO722xA				180	· · · · · · · · · · · · · · · · · · ·
	Part-to-part skew (2)	ISO722xB				17	
t _{sk(pp)}	Part-to-part skew V	ISO722xC					
		ISO722xM				5	ns
		ISO722xA			3	15	
t _{sk(o)}	Channel-to-channel output skew (3)	ISO722xB			0.6	3	
		ISO722xC/M			0.2	1	
t _r	Output signal rise time		0 5 4		2		
t _f	Output signal fall time		See Figure 1		2		ns
t _{fs}	Failsafe output delay time from input power loss		See Figure 2		3		μs
t _{jit(pp)}	Peak-to-peak eye-pattern jitter	ISO722xM	150 Mbps PRBS NRZ data, 5-bit max same polarity input, both channels, See Figure 4, Figure 17		1		ns
/			150 Mbps unrestricted bit run length data input, both channels, See Figure 4		2		

Also referred to as pulse skew.

 $t_{sk(pp)}$ is the magnitude of the difference in propagation delay times between any specified terminals of two devices when both devices

operate with the same supply voltages, at the same temperature, and have identical packages and test circuits. $t_{sk(0)}$ is the skew between specified outputs of a single device with all driving inputs connected together and the outputs switching in the same direction while driving identical specified loads.





ELECTRICAL CHARACTERISTICS: V_{CC1} at 3.3 V, V_{CC2} at 5 V⁽¹⁾ OPERATION

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT	
SUPPLY	CURRENT	<u>'</u>						
	ISO7220x	0	V V 0V 1 1		0.6	1		
	ISO7221x	Quiescent	$V_I = V_{CC}$ or 0 V, no load		4.3	9.5		
	ISO7220A, ISO7220B	4 1 1 1 1 1 1	O. F. Miller Instant Olerals Circuit and Instant		1	2		
I _{CC1}	ISO7221A, ISO7221B	1 Mbps	0.5 MHz Input Clock Signal, no load		5	11		
	ISO7220C, ISO7220M	25 Mbps	42 F Miller Innuit Clock Signal, no look		2	1 9.5 2		
	ISO7221C, ISO7221M	25 IVIDPS	12.5 MHz Input Clock Signal, no load		6	12	mA	
	ISO7220x	Quiescent	$V_1 = V_{CC}$ or 0 V, no load		16	31	mA	
	ISO7221x	Quiescent	$V_1 = V_{CC}$ or V_1 , no load		8.5	17		
	ISO7220A, ISO7220B	1 Mbps	0.5 MHz Input Clock Signal, no load		18	32		
I _{CC2}	ISO7221A, ISO7221B	1 Mbps	0.5 MHZ INPUT Clock Signal, no load		10	18		
	ISO7220C, ISO7220M	25 Mbps	42 F Miller Innuit Clock Signal, no look		20			
	ISO7221C, ISO7221M	25 IVIDPS	12.5 MHz Input Clock Signal, no load		12	22		
	•	ISO7220x		V _{CC} - 0.8				
V_{OH}	High-level output voltage	ISO7221x (3.3-V side)	I _{OH} = -4 mA, See Figure 1	V _{CC} - 0.4				
			I _{OH} = -20 μA, See Figure 1	V _{CC} - 0.1			V	
\/	Low-level output voltage		IOL = 4 mA, See Figure 1			0.4		
V _{OL}	Low-level output voltage		IOL = 20 μA, See Figure 1		0	0.1	1	
$V_{I(HYS)}$	Input threshold voltage hysteresis				150		mV	
I _{IH}	High-level input current		IN from 0 V or V			10		
I _{IL}	Low-level input current		IN from 0 V or V _{CC}	-10			μA	
Cı	Input capacitance to ground	ut capacitance to ground			1		pF	
CMTI	Common-mode transient immunity		V _I = V _{CC} or 0 V, See Figure 3	15	40		kV/μs	

⁽¹⁾ For the 5-V operation, V_{CC1} or V_{CC2} is specified from 4.5 V to 5.5 V. For the 3.3-V operation, V_{CC1} or V_{CC2} is specified from 3 V to 3.6 V.

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SWITCHING CHARACTERISTICS: V_{CC1} at 3.3 V, V_{CC2} at 5 V OPERTAION

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{pLH} , t _{pHL}	Propagation delay	ISO722xA		285	395	480	
PWD	Pulse-width distortion $ \mathbf{t}_{\mathrm{pHL}} - \mathbf{t}_{\mathrm{pLH}} ^{(1)}$				1	18	
t _{pLH} , t _{pHL}	Propagation delay	ISO722xB		45	58	75	
PWD	Pulse-width distortion $ t_{pHL} - t_{pLH} ^{(1)}$		See Figure 1		1	4	
t _{pLH} , t _{pHL}	Propagation delay	ISO722xC	See rigule 1	25	36	48	
PWD	Pulse-width distortion $ t_{pHL} - t_{pLH} ^{(1)}$				1	3	
t _{pLH} , t _{pHL}	Propagation delay	ISO722xM		7	12	21	
PWD	Pulse-width distortion $ t_{pHL} - t_{pLH} ^{(1)}$				0.5	1	ns
		ISO722xA				190	
	Part-to-part skew (2)	ISO722xB				17	
t _{sk(pp)}	Fait-to-pait skew ·	ISO722xC				10	
		ISO722xM				5	
		ISO722xA			3	15	
t _{sk(o)}	Channel-to-channel output skew (3)	ISO722xB			0.6	3	
		ISO7220C/M			0.2	1	
t _r	Output signal rise time		One Figure 4		1		
t _f	Output signal fall time		See Figure 1		1		
t _{fs}	Failsafe output delay time from input po	wer loss	See Figure 2		3		μs
t _{jit(pp)}	Peak-to-peak eye-pattern jitter	ISO722xM	150 Mbps PRBS NRZ data, 5-bit max same polarity input, both channels, See Figure 4, Figure 17		1		ns
, 417			150 Mbps unrestricted bit run length data input, both channels, See Figure 4		2		113

Also referred to as pulse skew.

 $t_{sk(pp)}$ is the magnitude of the difference in propagation delay times between any specified terminals of two devices when both devices operate with the same supply voltages, at the same temperature, and have identical packages and test circuits. $t_{sk(0)}$ is the skew between specified outputs of a single device with all driving inputs connected together and the outputs switching in the

same direction while driving identical specified loads.





ELECTRICAL CHARACTERISTICS: V_{CC1} and V_{CC2} at 3.3 $V^{(1)}$ OPERATION

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
SUPPL	Y CURRENT	<u> </u>				· ·	
	ISO7220x	0	V V 0 V 11		0.6	1	
	ISO7221x	Quiescent	$V_I = V_{CC}$ or 0 V, no load		4.3	9.5	
	ISO7220A, ISO7220B	1 Mbss	O.F.Mills Innut Clark Signal, no load		1	2	
I _{CC1}	ISO7221A, ISO7221B	1 Mbps	0.5 MHz Input Clock Signal, no load		5	11	
	ISO7220C, ISO7220M	OF Mhno	12 F MI In Innut Clock Signal, no load		2	4	
	ISO7221C, ISO7221M	25 Mbps	12.5 MHz Input Clock Signal, no load		6	12	A
	ISO7220x	0	V V 0 V 11		8	18	mA
	ISO7221x	Quiescent	$V_I = V_{CC}$ or 0 V, no load		4.3	9.5	
	ISO7220A, ISO7220B	1 Mbss	O.F.Mills Innut Clark Signal, no load		9	19	
I _{CC2}	ISO7221A, ISO7221B	1 Mbps	0.5 MHz Input Clock Signal, no load		5	11	
	ISO7220C, ISO7220M	25 Mbps	12 F MI In Innut Clock Signal, no load		10	20	
	ISO7221C, ISO7221M	25 Mibbs	12.5 MHz Input Clock Signal, no load		6	12	
1/	Lligh level output valtage	·	I _{OH} = -4 mA, See Figure 1	V _{CC} - 0.4	3		
V _{OH}	High-level output voltage		I _{OH} = -20 μA, See Figure 1	V _{CC} - 0.1	3.3		V
1/	Low lovel output voltage		I _{OL} = 4 mA, See Figure 1		0.2	0.4	V
V _{OL}	Low-level output voltage		I _{OL} = 20 μA, See Figure 1		0	0.1	
V _{I(HYS)}	Input voltage hysteresis				150		mV
I _{IH}	High-level input current		INI from O V or V			10	
I _{IL}	Low-level input current		IN from 0 V or V _{CC}	-10			μA
Cı	Input capacitance to ground		IN at V_{CC} , $V_I = 0.4 \sin (4E6\pi t)$		1		pF
CMTI	Common-mode transient immunity	,	V _I = V _{CC} or 0 V, See Figure 3	15	40		kV/μs

⁽¹⁾ For the 3.3-V operation, V_{CC1} or V_{CC2} is specified from 3 V to 3.6 V.



SWITCHING CHARACTERISTICS

V_{CC1} and V_{CC2} at 3.3 V operation, over recommended operating conditions (unless otherwise noted)

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
t_{pLH} , t_{pHL}	Propagation delay	ISO722xA		290	400	485	
PWD	Pulse-width distortion $ \mathbf{t}_{\mathrm{pHL}} - \mathbf{t}_{\mathrm{pLH}} ^{(1)}$				1	18	
t _{pLH} , t _{pHL}	Propagation delay	ISO722xB		46	62	78	
PWD	Pulse-width distortion $ t_{pHL} - t_{pLH} ^{(1)}$		Soo Figure 1		1	4	
t_{pLH} , t_{pHL}	Propagation delay	See Figure 1	26	40	52		
PWD	Pulse-width distortion $ t_{pHL} - t_{pLH} ^{(1)}$				1	3	
t _{pLH} , t _{pHL}	Propagation delay	ISO722xM		8	16	25	
PWD	Pulse-width distortion $ t_{pHL} - t_{pLH} ^{(1)}$				0.5	1	ns
		ISO722xA				190	
	Part-to-part skew ⁽²⁾	ISO722xB				17	
t _{sk(pp)}	Fait-to-pait skew	ISO722xC				10	
		ISO722xM				5	
		ISO722xA			3	15	
t _{sk(o)}	Channel-to-channel output skew (3)	ISO722xB			0.6	3	
		ISO722xC/M			0.2	1	
t _r	Output signal rise time		0 5		2		
t _f	Output signal fall time		See Figure 1		2		
t _{fs}	Failsafe output delay time from input power lo	oss	See Figure 2		3		μs
t _{jit(pp)} Peak-to-peak eye-pattern jitter		ISO722xM	150 Mbps PRBS NRZ data, 5-bit max same polarity input, both channels, See Figure 4, Figure 17		1		ns
/			150 Mbps unrestricted bit run length data input, both channels, See Figure 4		2		

Also referred to as pulse skew.

 $t_{sk(pp)}$ is the magnitude of the difference in propagation delay times between any specified terminals of two devices when both devices operate with the same supply voltages, at the same temperature, and have identical packages and test circuits. $t_{sk(0)}$ is the skew between specified outputs of a single device with all driving inputs connected together and the outputs switching in the

same direction while driving identical specified loads.







ELECTRICAL CHARACTERISTICS: V_{CC1} and V_{CC2} at 2.8 V (ISO722xC-only)⁽¹⁾ OPERATION

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
SUPPLY	CURRENT	<u> </u>		1		,	
ISO7220C		Outcocot	V V 270V 20 lood		0.4	0.9	
	ISO7221C	Quiescent	$V_I = V_{CC}$ or 0 V, no load		3.7	7.5	
I _{CC1}	ISO7220C	25 Mhna	12 F Mile Input Clock Signal, no look		1.5	3.5	
	ISO7221C	25 Mbps	12.5 MHz Input Clock Signal, no load		4.5	10	A
	ISO7220C	Quiescent	$V_1 = V_{CC}$ or 0 V, no load		6.8	15	mA
	ISO7221C	Quiescent	$V_1 = V_{CC}$ or V_1 , no load		3.7	7.5	
I _{CC2}	ISO7220C	25 Mbno	12.5 MHz Input Clock Signal, no load		9	17	
	ISO7221C	25 Mbps			4.5	10	
V	High-level output voltage		I _{OH} = -4 mA, See Figure 1	V _{CC} - 0.6	2.55		
V _{OH}	r ligh-level output voltage		$I_{OH} = -20 \mu A$, See Figure 1	V _{CC} - 0.1	2.8		V
V_{OL}	Low-level output voltage		I _{OL} = 4 mA, See Figure 1		0.25	0.6	V
VOL	Low-level output voltage		I _{OL} = 20 μA, See Figure 1		0	0.1	
$V_{I(HYS)}$	Input voltage hysteresis				150		mV
I _{IH}	High-level input current		IN from 0 V or V _{CC}			10	
$I_{\rm IL}$	Low-level input current		IN HOLL O V OF VCC	-10			μA
CI	Input capacitance to ground		IN at V_{CC} , $V_I = 0.4 \sin (4E6\pi t)$		1		pF
CMTI	Common-mode transient immunity		V _I = V _{CC} or 0 V, See Figure 3	10	30		kV/μs

^{(1) 2.8-}V operation is only guaranteed for ISO722xC with production screening starting in January 2012. The first two digits of the Lot Trace Code (YMSLLLLG4) written on top of each device can be used to identify year and month of production respectively.

ISO7220A, ISO7220B, ISO7220C, ISO7220M ISO7221A, ISO7221B, ISO7221C, ISO7221M

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SWITCHING CHARACTERISTICS

V_{CC1} and V_{CC2} at 2.8 V operation, over recommended operating conditions (unless otherwise noted)

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{pLH} , t _{pHL}	Propagation delay	ISO722xC	See Figure 1	26	45	65	
PWD	Pulse-width distortion $ t_{pHL} - t_{pLH} ^{(1)}$				1.5	5	
t _{sk(pp)}	Part-to-part skew ⁽²⁾	ISO722xC				12	ns
t _{sk(o)}	Channel-to-channel output skew (3)	ISO722xC			0.2	5	
t _r	Output signal rise time	<u>.</u>	0		2		
t _f	Output signal fall time		See Figure 1		2		
t _{fs}	Failsafe output delay time from input power	loss	See Figure 2		4.6		μs

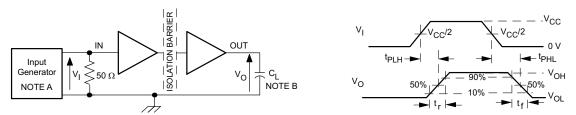
⁽¹⁾ Also referred to as pulse skew.

⁽²⁾ t_{sk(pp)} is the magnitude of the difference in propagation delay times between any specified terminals of two devices when both devices operate with the same supply voltages, at the same temperature, and have identical packages and test circuits.

⁽³⁾ $t_{sk(0)}$ is the skew between specified outputs of a single device with all driving inputs connected together and the outputs switching in the same direction while driving identical specified loads.

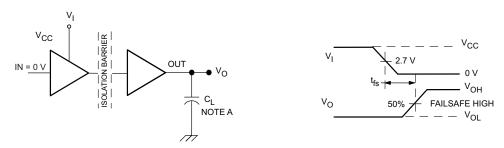


PARAMETER MEASUREMENT INFORMATION



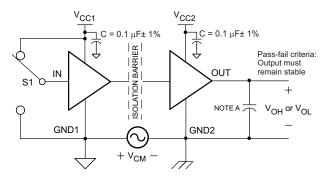
- A. The input pulse is supplied by a generator having the following characteristics: PRR \leq 50 kHz, 50% duty cycle, $t_r \leq$ 3 ns, $t_f \leq$ 3 ns, $Z_O = 50\Omega$.
- B. $C_L = 15$ pF and includes instrumentation and fixture capacitance within $\pm 20\%$.

Figure 1. Switching Characteristic Test Circuit and Voltage Waveforms



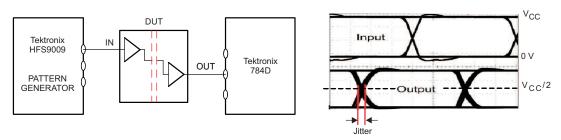
A. $C_L = 15 \text{ pF}$ and includes instrumentation and fixture capacitance within $\pm 20\%$.

Figure 2. Failsafe Delay Time Test Circuit and Voltage Waveforms



A. $C_L = 15 \text{ pF}$ and includes instrumentation and fixture capacitance within $\pm 20\%$.

Figure 3. Common-Mode Transient Immunity Test Circuit



NOTE: PRBS bit pattern run length is $2^{16} - 1$. Transition time is 800 ps.

Figure 4. Peak-to-Peak Eye-Pattern Jitter Test Circuit and Voltage Waveform



DEVICE INFORMATION

IEC PACKAGE CHARACTERISTICS

	PARAMETER	TEST CONDITIONS		MIN	TYP	MAX	UNIT
L(I01)	Minimum air gap (Clearance)	Shortest terminal-to-terminal distance through air		4.8			mm
L(102)	Minimum external tracking (Creepage)	Shortest terminal-to-terminal distance across the package surface	SOIC-8	4.3			mm
CTI	Tracking resistance (Comparative Tracking Index)	DIN IEC 60112 / VDE 0303 Part 1	•	≥400			V
	Minimum Internal Gap (Internal Clearance)	Distance through the insulation		0.008			mm
R _{IO}	Isolation resistance	Input to output, V_{IO} = 500 V, all pins on each side barrier tied together creating a two-terminal device $T_A < 100^{\circ} C$	of the e,		>10 ¹²		Ω
		Input to output, V _{IO} = 500 V, 100°C ≤ T _A ≤ max			>10 ¹¹		Ω
C _{IO}	Barrier capacitance Input to output	$V_1 = 0.4 \sin (4E6\pi t)$			1		pF
C _I	Input capacitance to ground	$V_I = 0.4 \sin (4E6\pi t)$			1		pF

NOTE: Creepage and clearance requirements should be applied according to the specific equipment isolation standards of an application. Care should be taken to maintain the creepage and clearance distance of a board design to ensure that the mounting pads of the isolator on the printed circuit board do not reduce this distance.

Creepage and clearance on a printed circuit board become equal according to the measurement techniques shown in the *Isolation Glossary*. Techniques such as inserting grooves and/or ribs on a printed circuit board are used to help increase these specifications.

IEC 60664-1 RATINGS TABLE

PARAMETER	TEST CONDITIONS	SPECIFICATION
Basic isolation group	Material group	II
	Rated mains voltage ≤150 V _{RMS}	I-IV
Installation classification	Rated mains voltage ≤300 V _{RMS}	1-111
	Rated mains voltage ≤400 V _{RMS}	1-11

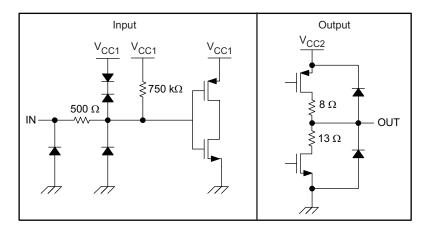
IEC 60747-5-2 INSULATION CHARACTERISTICS (1)

	PARAMETER	TEST CONDITIONS	SPECIFICATION	UNIT
V _{IORM}	Maximum working insulation voltage		560	
V _{PR}	Input to output test voltage	Method b1, V _{PR} = V _{IORM} × 1.875, 100% Production test with t = 1 s, Partial discharge <5 pC	1050	V _{PK}
V_{IOTM}	Transient overvoltage	t = 60 s	4000	
R _S	Insulation resistance	$V_{IO} = 500 \text{ V at T}_{S}$	>10 ⁹	Ω
	Pollution degree		2	

(1) Climatic Classification 40/125/21



DEVICE I/O SCHEMATICS



IEC SAFETY LIMITING VALUES

Safety limiting intends to prevent potential damage to the isolation barrier upon failure of input or output circuitry. A failure of the IO can allow low resistance to ground or the supply and, without current limiting, dissipate sufficient power to overheat the die and damage the isolation barrier potentially leading to secondary system failures.

	PARAMETER	MIN	TYP	MAX	UNIT		
	Safety input, output, or	SOIC-8	$\theta_{JA} = 212^{\circ}\text{C/W}, \ V_{I} = 5.5 \ \text{V}, \ T_{J} = 170^{\circ}\text{C}, \ T_{A} = 25^{\circ}\text{C}$			124	A
IS	supply current	30IC-8	$\theta_{JA} = 212^{\circ}\text{C/W}, \ V_{I} = 3.6 \ \text{V}, \ T_{J} = 170^{\circ}\text{C}, \ T_{A} = 25^{\circ}\text{C}$			190	mA
Ts	Maximum case temperature	SOIC-8				150	°C

The safety-limiting constraint is the absolute maximum junction temperature specified in the absolute maximum ratings table. The power dissipation and junction-to-air thermal impedance of the device installed in the application hardware determines the junction temperature. The assumed junction-to-air thermal resistance in the Thermal Characteristics table is that of a device installed in the JESD51-3, Low Effective Thermal Conductivity Test Board for Leaded Surface Mount Packages and is conservative. The power is the recommended maximum input voltage times the current. The junction temperature is then the ambient temperature plus the power times the junction-to-air thermal resistance.



SOIC-8 PACKAGE THERMAL CHARACTERISTICS

over recommended operating conditions (unless otherwise noted)

PARAMETER			TEST CONDITIONS	MIN	TYP	MAX	UNIT
0	θ _{IA} Junction-to-air		Low-K Thermal Resistance ⁽¹⁾		212		
OJA			High-K Thermal Resistance		122		°C/W
θ_{JB}	Junction-to-Board Thermal Resistance				37		C/VV
θ_{JC}	Junction-to-Case Thermal F	Resistance			69.1		
P_D	Device Power Dissipation ISO722xM		$V_{CC1} = V_{CC2} = 5.5 \text{ V}, T_J = 150^{\circ}\text{C}, C_L = 15 \text{ pF},$ Input a 150 Mbps 50% duty cycle square wave			390	mW

(1) Tested in accordance with the Low-K or High-K thermal metric definitions of EIA/JESD51-3 for leaded surface mount packages.

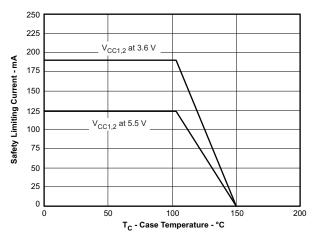


Figure 5. SOIC-8 θ_{JC} THERMAL DERATING CURVE per IEC 60747-5-2

DEVICE FUNCTION TABLE

Table 1. ISO7220x or ISO7221x⁽¹⁾

INPUT SIDE V _{CC}	OUTPUT SIDE V _{CC}	INPUT IN	OUTPUT OUT
		Н	Н
PU	PU	L	L
		Open	Н
PD	PU	X	Н

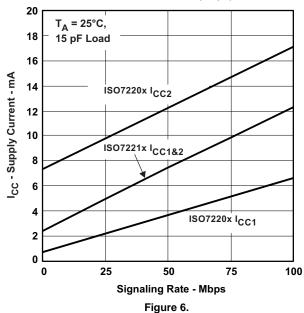
⁽¹⁾ $PU = Powered Up(Vcc \ge 3.0V)$; $PD = Powered Down (Vcc \le 2.5V)$; X = Irrelevant; H = High Level; L = Low Level



TYPICAL CHARACTERISTIC CURVES

3.3-V RMS SUPPLY CURRENT

SIGNALING RATE (Mbps)



PROPAGATION DELAY

VS FREE-AIR TEMPERATURE, ISO722xA

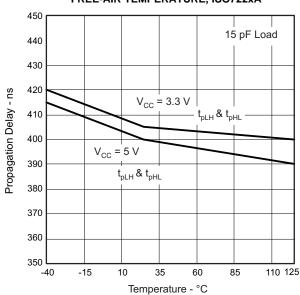


Figure 8.

5-V RMS SUPPLY CURRENT

SIGNALING RATE (Mbps)

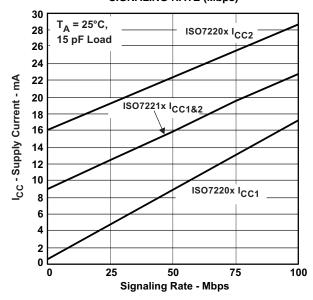
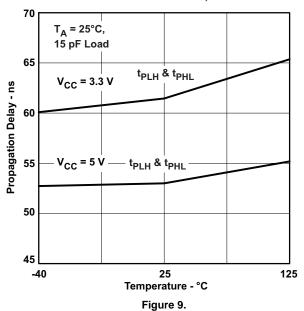


Figure 7.

PROPAGATION DELAY

FREE-AIR TEMPERATURE, ISO722xB



17



TYPICAL CHARACTERISTIC CURVES (continued)

PROPAGATION DELAY

FREE-AIR TEMPERATURE, ISO722xC

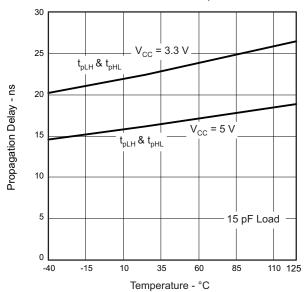


Figure 10.

PROPAGATION DELAY

VS

FREE-AIR TEMPERATURE, ISO722xM

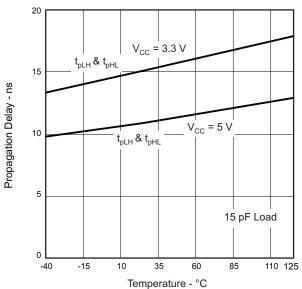


Figure 11.

ISO722xA, ISO722xB AND ISO722xC INPUT VOLTAGE LOW-TO-HIGH SWITCHING THRESHOLD

vs FREE-AIR TEMPERATURE

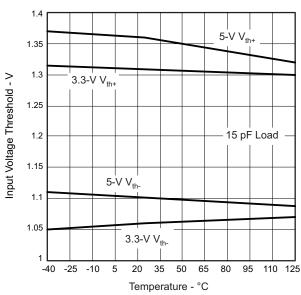


Figure 12.

ISO722xM INPUT VOLTAGE HIGH-TO-LOW

FREE-AIR TEMPERATURE

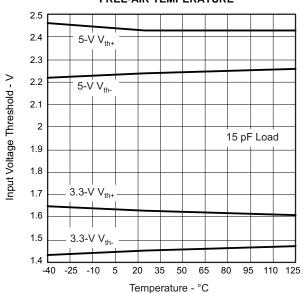
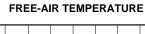


Figure 13.



TYPICAL CHARACTERISTIC CURVES (continued)





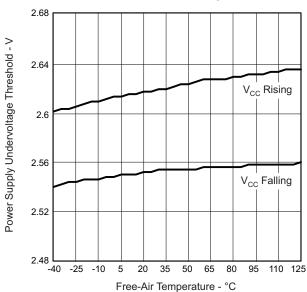
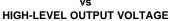


Figure 14.

HIGH-LEVEL OUTPUT CURRENT



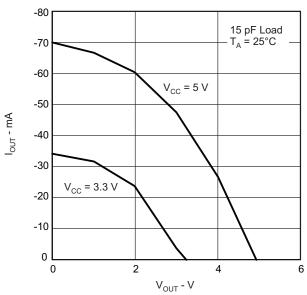


Figure 15.

LOW-LEVEL OUTPUT CURRENT LOW-LEVEL OUTPUT VOLTAGE

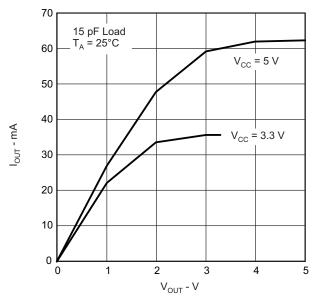


Figure 16.

ISO722xM JITTER **SIGNALING RATE**

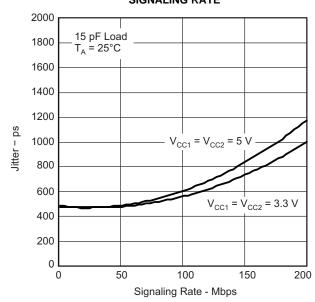


Figure 17.



APPLICATION INFORMATION

Typical Applications

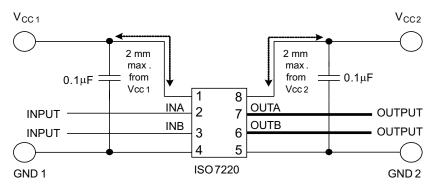


Figure 18. Typical ISO7220 Application Circuit

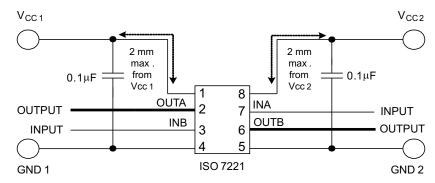


Figure 19. Typical ISO7221 Application Circuit

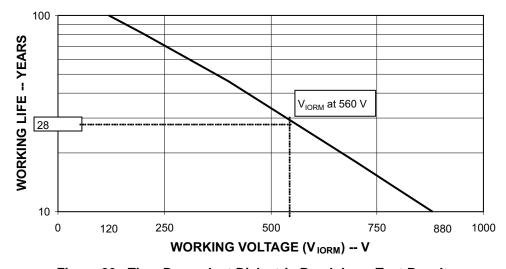
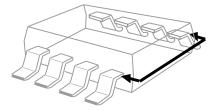


Figure 20. Time Dependent Dielectric Breakdown Test Results

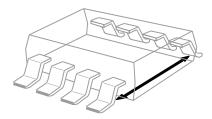


ISOLATION GLOSSARY

Creepage Distance — The shortest path between two conductive input to output leads measured along the surface of the insulation. The shortest distance path is found around the end of the package body.



Clearance — The shortest distance between two conductive input to output leads measured through air (line of sight).



Input-to Output Barrier Capacitance — The total capacitance between all input terminals connected together, and all output terminals connected together.

Input-to Output Barrier Resistance — The total resistance between all input terminals connected together, and all output terminals connected together.

Primary Circuit — An internal circuit directly connected to an external supply mains or other equivalent source which supplies the primary circuit electric power.

Secondary Circuit — A circuit with no direct connection to primary power, and derives its power from a separate isolated source.

Comparative Tracking Index (CTI) — CTI is an index used for electrical insulating materials which is defined as the numerical value of the voltage which causes failure by tracking during standard testing. Tracking is the process that produces a partially conducting path of localized deterioration on or through the surface of an insulating material as a result of the action of electric discharges on or close to an insulation surface -- the higher CTI value of the insulating material, the smaller the minimum creepage distance.

Generally, insulation breakdown occurs either through the material, over its surface, or both. Surface failure may arise from flashover or from the progressive degradation of the insulation surface by small localized sparks. Such sparks are the result of the breaking of a surface film of conducting contaminant on the insulation. The resulting break in the leakage current produces an overvoltage at the site of the discontinuity, and an electric spark is generated. These sparks often cause carbonization on insulation material and lead to a carbon track between points of different potential. This process is known as *tracking*.

ISO7220A, ISO7220B, ISO7220C, ISO7220M ISO7221A, ISO7221B, ISO7221C, ISO7221M

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INSTRUMENTS

Insulation:

Operational insulation — Insulation needed for the correct operation of the equipment.

Basic insulation — Insulation to provide basic protection against electric shock.

Supplementary insulation — Independent insulation applied in addition to basic insulation in order to ensure protection against electric shock in the event of a failure of the basic insulation.

Double insulation — Insulation comprising both basic and supplementary insulation.

Reinforced insulation — A single insulation system which provides a degree of protection against electric shock equivalent to double insulation.

Pollution Degree:

Pollution Degree 1 — No pollution, or only dry, nonconductive pollution occurs. The pollution has no influence.

Pollution Degree 2 — Normally, only nonconductive pollution occurs. However, a temporary conductivity caused by condensation must be expected.

Pollution Degree 3 — Conductive pollution occurs or dry nonconductive pollution occurs which becomes conductive due to condensation which is to be expected.

Pollution Degree 4 - Continuous conductivity occurs due to conductive dust, rain, or other wet conditions.

Installation Category:

Overvoltage Category — This section is directed at insulation co-ordination by identifying the transient overvoltages which may occur, and by assigning 4 different levels as indicated in IEC 60664.

- I: Signal Level Special equipment or parts of equipment.
- II: Local Level Portable equipment etc.
- III: Distribution Level Fixed installation
- IV: Primary Supply Level Overhead lines, cable systems

Each category should be subject to smaller transients than the category above.

REVISION HISTORY

Cl	hanges from Original (July 2006) to Revision A	Page
•	Deleted "and CSA Apporved" from the UL 1577 FEATURES bullet	1
<u>.</u>	Added option A to the AVAILABLE OPTIONS table	2
Cł	hanges from Revision A (August 2006) to Revision B	Page
•	Added the ELECTICAL CHARACTERISTICS tables to the data sheet	3
•	Added the PARAMETER MEASUREMENT INFORMATION to the data sheet	13
•	Added the DEVICE INFORMATION section to the data sheet	14
•	Added the TYPICAL CHARACTERISTIC CURVES to the data sheet	17
•	Added the APPLICATION INFORMATION section to the data sheet	20
•	Added the ISOLATION GLOSSARY section to the data sheet	21



Changes from Revision B (May 2007) to Revision C Page Added Figure 17 cross reference to the Peak-to-peak eye-pattern jitter of the SWITCHING CHARACTERISTICS Added Figure 17 cross reference to the Peak-to-peak eye-pattern jitter of the SWITCHING CHARACTERISTICS table 6 Added Figure 17 cross reference to the Peak-to-peak eye-pattern jitter of the SWITCHING CHARACTERISTICS Added Figure 17 cross reference to the Peak-to-peak eye-pattern jitter of the SWITCHING CHARACTERISTICS Changed the IEC 60664-1 RATINGS TABLE - Specification I-III test conditions From: Rated mains voltage ≤150 Changes from Revision C (May 2007) to Revision D Page Changes from Revision D (June 2007) to Revision E Page Changes from Revision E (July 2007) to Revision F **Page** Added t_{sk(pp)} footnote to the SWITCHING CHARACTERISTICS: V_{CC1} at 5 V, V_{CC2} at 3.3 V OPERATION table 6 Changes from Revision F (August 2007) to Revision G Page Added Part Numbers ISO720B and ISO7221B to the ELECTRICAL CHARACTERISTICS: V_{CC1} and V_{CC2} at 5-V Added Part Numbers ISO720B and ISO7221B to the ELECTRICAL CHARACTERISTICS: V_{CC1} at 5 V, V_{CC2} at 3.3 V Added Part Numbers ISO720B and ISO7221B to the ELECTRICAL CHARACTERISTICS: V_{CC1} at 3.3 V, V_{CC2} at 5 V Added Part Numbers ISO720B and ISO7221B to the ELECTRICAL CHARACTERISTICS: V_{CC1} and V_{CC2} at 3.3 V9





	nanges from Revision G (March 2008) to Revision H	age
•	Added Note: (1) to the RECOMMENDED OPERATING CONDITIONS table	3
•	Added Note: (1) to the ELECTRICAL CHARACTERISTICS: V _{CC1} and V _{CC2} at 5-V table	4
•	Added Note: (1) to the ELECTRICAL CHARACTERISTICS: V _{CC1} at 5 V, V _{CC2} at 3.3 V table	5
•	Added Note (1): to the ELECTRICAL CHARACTERISTICS: V _{CC1} at 3.3 V, V _{CC2} at 5 V table	7
•	Added Note (1): to the ELECTRICAL CHARACTERISTICS: V _{CC1} and V _{CC2} at 3.3 V	
Ch	nanges from Revision H (May 2008) to Revision I	age
•	Added "IEC 61010-1, IEC 60950-1 and CSA Approved" to the UL 1577 FEATURES bullet	1
Ch	nanges from Revision I (December 2008) to Revision J	age
•	Changed ISO7221C Marked As column From: TI7221C To: I7221C in the AVAILABLE OPTIONS table	2
Ch	nanges from Revision J (May 2009) to Revision K	age
•	Changed column 2 of the AVAILABLE OPTIONS table From: Signaling Rate To: Max Signaling Rate	2
•	Changed the the RECOMMENDED OPERATING CONDITIONS so that Note (2) is associated with all device options in the Input pulse width and Signaling rate	
•	Changed Note (2) From: Typical signaling rate under ideal conditions at 25°C. To: Typical signaling rate and Input pulse width are measured at ideal conditions at 25°C.	
Ch	nanges from Revision K (January 2010) to Revision L	
•		age
	Changed Feature From: 4000-V _{peak} Isolation, 560 V _{peak} V _{IORM} To: 4000-V _{PK} V _{IOTM} , 560 V _{PK} V _{IORM} per IEC 60747-5-2 (VDE 0884, Rev2)	
•	Changed Feature From: 4000-V _{peak} Isolation, 560 V _{peak} V _{IORM} To: 4000-V _{PK} V _{IOTM} , 560 V _{PK} V _{IORM} per IEC 60747-5-2 (VDE 0884, Rev2)	1
•	(VDE 0884, Rev2)	1
	(VDE 0884, Rev2)	1
•	(VDE 0884, Rev2)	1
•	(VDE 0884, Rev2)	1 3 3 3
•	(VDE 0884, Rev2) Changed Feature From: Operates with 3.3-V or 5-V Supplies To: Operates with 2.8-V (C-Grade), 3.3-V or 5-V Supplies Changed the REGULATORY INFORMATION table Added device options to V _{CC} in the RECOMMENDED OPERATING CONDITIONS table Changed Note: (1) in the RECOMMENDED OPERATING CONDITIONS table Changed I _{CC1} and I _{CC2} test conditions in the 5-V table	1 3 3 3
•	(VDE 0884, Rev2) Changed Feature From: Operates with 3.3-V or 5-V Supplies To: Operates with 2.8-V (C-Grade), 3.3-V or 5-V Supplies Changed the REGULATORY INFORMATION table Added device options to V _{CC} in the RECOMMENDED OPERATING CONDITIONS table Changed Note: (1) in the RECOMMENDED OPERATING CONDITIONS table Changed I _{CC1} and I _{CC2} test conditions in the 5-V table Changed Table Note: (1)	1 3 3 3 4 4
•	(VDE 0884, Rev2) Changed Feature From: Operates with 3.3-V or 5-V Supplies To: Operates with 2.8-V (C-Grade), 3.3-V or 5-V Supplies Changed the REGULATORY INFORMATION table Added device options to V _{CC} in the RECOMMENDED OPERATING CONDITIONS table Changed Note: (1) in the RECOMMENDED OPERATING CONDITIONS table Changed I _{CC1} and I _{CC2} test conditions in the 5-V table	1 3 3 3 4 4 5
•	(VDE 0884, Rev2) Changed Feature From: Operates with 3.3-V or 5-V Supplies To: Operates with 2.8-V (C-Grade), 3.3-V or 5-V Supplies Changed the REGULATORY INFORMATION table Added device options to V _{CC} in the RECOMMENDED OPERATING CONDITIONS table Changed Note: (1) in the RECOMMENDED OPERATING CONDITIONS table Changed I _{CC1} and I _{CC2} test conditions in the 5-V table Changed Table Note: (1) Changed I _{CC1} and I _{CC2} test conditions in the V _{CC1} at 5 V, V _{CC2} at 3.3 V table	1 3 3 3 4 4 5
•	Changed Feature From: Operates with 3.3-V or 5-V Supplies To: Operates with 2.8-V (C-Grade), 3.3-V or 5-V Supplies Changed the REGULATORY INFORMATION table Added device options to V _{CC} in the RECOMMENDED OPERATING CONDITIONS table Changed Note: (1) in the RECOMMENDED OPERATING CONDITIONS table Changed I _{CC1} and I _{CC2} test conditions in the 5-V table Changed Table Note: (1) Changed I _{CC1} and I _{CC2} test conditions in the V _{CC1} at 5 V, V _{CC2} at 3.3 V table Changed Table Note: (1) Changed I _{CC1} and I _{CC2} test conditions in the V _{CC1} at 3.3 V, V _{CC2} at 5 V table	1 3 3 4 5 5 7
	(VDE 0884, Rev2) Changed Feature From: Operates with 3.3-V or 5-V Supplies To: Operates with 2.8-V (C-Grade), 3.3-V or 5-V Supplies Changed the REGULATORY INFORMATION table Added device options to V _{CC} in the RECOMMENDED OPERATING CONDITIONS table Changed Note: (1) in the RECOMMENDED OPERATING CONDITIONS table Changed I _{CC1} and I _{CC2} test conditions in the 5-V table Changed Table Note: (1) Changed I _{CC1} and I _{CC2} test conditions in the V _{CC1} at 5 V, V _{CC2} at 3.3 V table Changed Table Note: (1)	1 3 3 4 4 5 7 7
• • • • • • • • • • • • • • • • • • • •		1 3 3 4 4 5 5 7 7 9
•	$ (\text{VDE } 0884, \text{Rev2}) \dots \\ \text{Changed Feature From: Operates with } 3.3\text{-V or } 5\text{-V Supplies To: Operates with } 2.8\text{-V (C-Grade), } 3.3\text{-V or } 5\text{-V Supplies } \\ \text{Changed the REGULATORY INFORMATION table} \\ \text{Added device options to V}_{\text{CC}} \text{ in the RECOMMENDED OPERATING CONDITIONS table} \\ \text{Changed Note: (1) in the RECOMMENDED OPERATING CONDITIONS table} \\ \text{Changed I}_{\text{CC1}} \text{ and I}_{\text{CC2}} \text{ test conditions in the } 5\text{-V table} \\ \text{Changed Table Note: (1)} \\ \text{Changed I}_{\text{CC1}} \text{ and I}_{\text{CC2}} \text{ test conditions in the V}_{\text{CC1}} \text{ at } 5\text{ V, V}_{\text{CC2}} \text{ at } 3.3\text{ V table} \\ \text{Changed I}_{\text{CC1}} \text{ and I}_{\text{CC2}} \text{ test conditions in the V}_{\text{CC1}} \text{ at } 3.3\text{ V, V}_{\text{CC2}} \text{ at } 5\text{ V table} \\ \text{Changed I}_{\text{CC1}} \text{ and I}_{\text{CC2}} \text{ test conditions in the V}_{\text{CC1}} \text{ at } 3.3\text{ V, V}_{\text{CC2}} \text{ at } 5\text{ V table} \\ \text{Changed I}_{\text{CC1}} \text{ and I}_{\text{CC2}} \text{ test conditions in the V}_{\text{CC1}} \text{ and V}_{\text{CC2}} \text{ at } 3.3\text{ V table} \\ \text{Changed I}_{\text{CC1}} \text{ and I}_{\text{CC2}} \text{ test conditions in the V}_{\text{CC1}} \text{ and V}_{\text{CC2}} \text{ at } 3.3\text{ V table} \\ \text{Changed I}_{\text{CC1}} \text{ and I}_{\text{CC2}} \text{ test conditions in the V}_{\text{CC1}} \text{ and V}_{\text{CC2}} \text{ at } 3.3\text{ V table} \\ \text{Changed I}_{\text{CC1}} \text{ and I}_{\text{CC2}} \text{ test conditions in the V}_{\text{CC1}} \text{ and V}_{\text{CC2}} \text{ at } 3.3\text{ V table} \\ \text{Changed I}_{\text{CC1}} \text{ and I}_{\text{CC2}} \text{ test conditions in the V}_{\text{CC1}} \text{ and V}_{\text{CC2}} \text{ at } 3.3\text{ V table} \\ \text{Changed I}_{\text{CC1}} \text{ and I}_{\text{CC2}} \text{ test conditions in the V}_{\text{CC1}} \text{ and V}_{\text{CC2}} \text{ at } 3.3\text{ V table} \\ \text{Changed I}_{\text{CC1}} \text{ and I}_{\text{CC2}} \text{ test conditions in the V}_{\text{CC1}} \text{ and V}_{\text{CC2}} \text{ at } 3.3\text{ V table} \\ \text{Changed I}_{\text{CC1}} \text{ and I}_{\text{CC2}} \text{ test conditions in the V}_{\text{CC1}} \text{ and I}_{\text{CC2}} \text{ at } 3.3\text{ V table} \\ \text{Changed I}_{\text{CC1}} \text{ and I}_{\text{CC2}} \text{ test conditions in the V}_{\text{CC1}} \text{ and I}_{\text{CC2}} \text{ at } 3.3\text{ V table} \\ \text{Changed I}_{\text{CC1}} \text{ and I}_{\text{CC2}} test conditio$	1 3 3 4 5 5 7 9 9
	(VDE 0884, Rev2)	1 3 3 4 5 7 7 9 9 9 11
• • • • • • • • • • • • • • • • • • • •	Changed Feature From: Operates with 3.3-V or 5-V Supplies To: Operates with 2.8-V (C-Grade), 3.3-V or 5-V Supplies Changed the REGULATORY INFORMATION table Added device options to V _{CC} in the RECOMMENDED OPERATING CONDITIONS table Changed Note: (1) in the RECOMMENDED OPERATING CONDITIONS table Changed I _{CC1} and I _{CC2} test conditions in the 5-V table Changed Table Note: (1) Changed I _{CC1} and I _{CC2} test conditions in the V _{CC1} at 5 V, V _{CC2} at 3.3 V table Changed Table Note: (1) Changed I _{CC1} and I _{CC2} test conditions in the V _{CC1} at 3.3 V, V _{CC2} at 5 V table Changed Table Note (1) Changed Table Note (1) Changed I _{CC1} and I _{CC2} test conditions in the V _{CC1} at 3.3 V, V _{CC2} at 3.3 V table Changed Table Note (1) Added ELECTRICAL and Switching CHARACTERISTICS table for V _{CC1} and V _{CC2} at 2.8 V (ISO722xC-only)	1 3 3 4 5 5 7 9 9 9 11 13
• • • • • • • • • • • • • • • • • • • •	Changed Feature From: Operates with 3.3-V or 5-V Supplies To: Operates with 2.8-V (C-Grade), 3.3-V or 5-V Supplies	1 3 3 4 5 7 9 11 13 14





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PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead/Ball Finish (6)	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
ISO7220AD	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	I7220A	Samples
ISO7220ADG4	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	I7220A	Samples
ISO7220ADR	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	17220A	Samples
ISO7220ADRG4	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	17220A	Samples
ISO7220BD	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	I7220B	Samples
ISO7220BDG4	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	I7220B	Samples
ISO7220BDR	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	I7220B	Samples
ISO7220BDRG4	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	I7220B	Samples
ISO7220CD	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	17220C	Samples
ISO7220CDG4	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	17220C	Samples
ISO7220CDR	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	17220C	Samples
ISO7220CDRG4	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	17220C	Samples
ISO7220MD	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	I7220M	Samples
ISO7220MDG4	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	I7220M	Samples
ISO7220MDR	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	17220M	Samples
ISO7220MDRG4	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	I7220M	Samples
ISO7221AD	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	I7221A	Samples





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Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
ISO7221ADG4	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	I7221A	Samples
ISO7221ADR	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	I7221A	Samples
ISO7221ADRG4	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	I7221A	Samples
ISO7221BD	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	I7221B	Samples
ISO7221BDG4	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	I7221B	Samples
ISO7221BDR	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	I7221B	Samples
ISO7221BDRG4	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	I7221B	Samples
ISO7221CD	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	17221C	Samples
ISO7221CDG4	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	17221C	Samples
ISO7221CDR	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	17221C	Samples
ISO7221CDRG4	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	17221C	Sample
ISO7221MD	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	I7221M	Sample
ISO7221MDG4	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	I7221M	Sample
ISO7221MDR	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	I7221M	Sample
ISO7221MDRG4	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	17221M	Sample

⁽¹⁾ The marketing status values are defined as follows: **ACTIVE:** Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

PACKAGE OPTION ADDENDUM



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(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead/Ball Finish Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

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OTHER QUALIFIED VERSIONS OF ISO7220A, ISO7221A, ISO7221C:

Automotive: ISO7220A-Q1, ISO7221A-Q1, ISO7221C-Q1

NOTE: Qualified Version Definitions:

Automotive - Q100 devices qualified for high-reliability automotive applications targeting zero defects

PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
ISO7220ADR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
ISO7220BDR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
ISO7220CDR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
ISO7220MDR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
ISO7221ADR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
ISO7221BDR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
ISO7221CDR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
ISO7221MDR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1

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*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)	
ISO7220ADR	SOIC	D	8	2500	367.0	367.0	35.0	
ISO7220BDR	SOIC	D	8	2500	367.0	367.0	35.0	
ISO7220CDR	SOIC	D	8	2500	367.0	367.0	35.0	
ISO7220MDR	SOIC	D	8	2500	367.0	367.0	35.0	
ISO7221ADR	SOIC	D	8	2500	367.0	367.0	35.0	
ISO7221BDR	SOIC	D	8	2500	367.0	367.0	35.0	
ISO7221CDR	SOIC	D	8	2500	367.0	367.0	35.0	
ISO7221MDR	SOIC	D	8	2500	367.0	367.0	35.0	

D (R-PDSO-G8)

PLASTIC SMALL OUTLINE



NOTES:

- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
- E. Reference JEDEC MS-012 variation AA.



D (R-PDSO-G8)

PLASTIC SMALL OUTLINE



NOTES:

- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



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